



Non-Contact Sheet Resistance Mapper

DATA SHEET - EddyCus[®] TF map 5050 series

HIGHLIGHTS

- Contact-free & real-time
- Accurate high resolution imaging system
 - sheet resistance imaging (Ohm/sq)
 - Layer thickness imaging of metal films (nm)
 - Substrate thickness of metal foils (µm)
- Mapping of encapsulated layers
- Multiple possibilities of analyzing the mapping by an easy-to-handle software

APPLICATIONS

- > Touch Panel Sensor
- > OLED & LED applications
- > Smart-glass applications
- > Photovoltaic
- > Semiconductors
- > De-icing & heating applications
- > Batteries & fuel cells
- > Packaging materials

MATERIALS

- Printed films
- Graphene, CNT
- Conductive oxides
- Metal films and meshes
- Other conductive layers



DATA SHEET

EddyCus® TF map 5050 series – Sheet Resistance Mapping



EddyCus® TF map 5050SR series

Measurement technology	Non-contact eddy current sensor
Substrates	e.g. foil, glass, wafer
Max. scanning area	20 inch / 508 x 508 mm (larger on request)
Edge effect correction / exclusion	2 mm edge exclusion for standard size
Max. sample thickness/ sensor gap	2 / 5 / 10 / 25 mm (defined by the thickest sample/ application)
Sheet resistance range and accuracy	0.001 – 10 Ohm/sq < 2% accuracy 10 – 100 Ohm/sq < 3% accuracy 100 – 1,000 Ohm/sq < 5% accuracy
Thickness mapping of metal films (e.g. Aluminum, Copper)	2 nm – 2 mm (in accordance with sheet resistance)
Scanning pitch	1 / 2 / 5 mm / 10 mm (other on request)
Measurement points per time (quadratic shape)	10,000 measurement points in 5 minutes 1,000,000 measurement points in 30 minutes
Scanning time	8 inch / 200 x 200 mm in 1.5 to 15 minutes (1 – 10 mm pitch) 12 inch / 300 x 300 mm in 3 to 30 minutes (1 – 10 mm pitch)
Device dimension (w/h/d) / Weight	46.5 x 11.4 x 35.4 inch / 1180 x 290 x 900 mm / 120 kg
Available features	Metal thickness tester Anisotropy sheet resistance sensor Optical transmission sensors at 632 nm wavelength

SOFTWARE & HANDLING – Sheet Resistance Analyzer 2.0

